TISP3180 DUAL SYMMETRICAL TRANSIENT VOLTAGE SUPPRESSORS

NOVEMBER 1986 - REVISED SEPTEMBER 199

TELECOMMUNICATION SYSTEM SECONDARY PROTECTION

Ion-Implanted Breakdown Region Precise and Stable Voltage Low Voltage Overshoot under Surge

| DEVICE | V _(Z) | V _(BO) | | |
|--------|------------------|-------------------|--|--|
| DEVICE | v | v | | |
| '3180 | 145 | 180 | | |

- **Planar Passivated Junctions** Low Off-State Current < 10 µA
- **Rated for International Surge Wave Shapes**

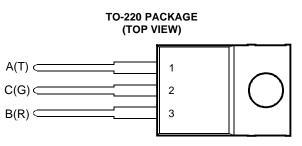
| WAVE SHAPE | STANDARD | I _{TSP} A |
|------------|------------------|-----------------------|
| 8/20 µs | ANSI C62.41 | 150 |
| 10/160 µs | FCC Part 68 | 60 |
| 10/560 µs | FCC Part 68 | 45 |
| 0.5/700 µs | RLM 88 | 38 |
| | FTZ R12 | 50 |
| 10/700 µs | VDE 0433 | 50 |
| | CCITT IX K17/K20 | 50 |
| 10/1000 µs | REA PE-60 | 50 |

UL Recognized, E132482

description

The TISP3180 is designed specifically for telephone equipment protection against lightning and transients induced by a.c. power lines. These devices consist of two bidirectional suppressor elements connected to a Common (C) terminal. They will supress voltage transients between terminals A and C, B and C, and A and Β.

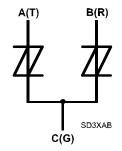
Transients are initially clipped by zener action until the voltage rises to the breakover level, which causes the device to crowbar. The high crowbar holding current prevents d.c. latchup as the transient subsides.



Pin 2 is in electrical contact with the mounting base.

MDXXANA

device symbol



These monolithic protection devices are fabricated in ion-implanted planar structures to ensure precise and matched breakover control and are virtually transparent to the system in normal operation



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absolute maximum ratings at 25°C case temperature (unless otherwise noted)

| RATING | SYMBOL | VALUE | UNIT | |
|--|---------------------|-------------|-------|--|
| Non-repetitive peak on-state pulse current (see Notes 1, 2 and 3) | | | | |
| 8/20 μs (ANSI C62.41, open-circuit voltage wave shape 1.2/50 μs) | | 150 | | |
| 10/160 µs (FCC Part 68, open-circuit voltage wave shape 10/160 µs) | | 60 | | |
| 5/200 µs (VDE 0433, open-circuit voltage wave shape 2 kV, 10/700 µs) | | 50 | | |
| 0.2/310 μs (RLM 88, open-circuit voltage wave shape 1.5 kV, 0.5/700 μs) | I _{TSP} | 38 | А | |
| 5/310 μs (CCITT IX K17/K20, open-circuit voltage wave shape 1.5 kV, 10/700 μs) | | 50 | | |
| 5/310 μs (FTZ R12, open-circuit voltage wave shape 2 kV, 10/700 μs) | | 50 | | |
| 10/560 μs (FCC Part 68, open-circuit voltage wave shape 10/560 μs) | | 45 | | |
| 10/1000 μs (REA PE-60, open-circuit voltage wave shape 10/1000 μs) | | 50 | | |
| Non-repetitive peak on-state current, 50 Hz, 2.5 s (see Notes 1 and 2) | I _{TSM} | 10 | A rms | |
| Initial rate of rise of on-state current, Linear current ramp, Maximum ramp value < 38 A | di _T /dt | 250 | A/µs | |
| Junction temperature | Т _Ј | 150 | °C | |
| Operating free - air temperature range | | 0 to 70 | °C | |
| Storage temperature range | T _{stg} | -40 to +150 | °C | |
| Lead temperature 1.5 mm from case for 10 s | T _{lead} | 260 | °C | |

NOTES: 1. Above 70°C, derate linearly to zero at 150°C case temperature

- 2. This value applies when the initial case temperature is at (or below) 70°C. The surge may be repeated after the device has returned to thermal equilibrium.
 - 3. Most PTT's quote an unloaded voltage waveform. In operation the TISP essentially shorts the generator output. The resulting loaded current waveform is specified.

electrical characteristics for the A and B terminals, $T_J = 25^{\circ}C$

| | PARAMETER | | TEST CONDIT | ONS | MIN | TYP | MAX | UNIT |
|----------------|------------------------------|------------------|-------------|--------------|-------|-----|------|------|
| VZ | Reference zener voltage | $I_Z = \pm 1 mA$ | | | ± 290 | | | V |
| I _D | Off-state leakage current | $V_D = \pm 50 V$ | | | | | ± 10 | μΑ |
| Coff | Off-state capacitance | $V_{D} = 0$ | f = 1 kHz | (see Note 4) | | 0.5 | 5 | pF |

NOTE 4: These capacitance measurements employ a three terminal capacitance bridge incorporating a guard circuit. The third terminal is connected to the guard terminal of the bridge.

electrical characteristics for the A and C or the B and C terminals, $T_J = 25^{\circ}C$

| | PARAMETER | | TEST CONDITIONS | | MIN | TYP | MAX | UNIT |
|-------------------|---|-------------------------|---------------------|--------------|--------|-------|-------|-------|
| VZ | Reference zener voltage | $I_Z = \pm 1 \text{mA}$ | | | ± 145 | | | V |
| ∝VZ | Temperature coefficient of reference voltage | | | | | 0.1 | | %/ºC |
| V _(BO) | Breakover voltage | (see Notes 5 and 6) | | | | | ± 180 | V |
| I _(BO) | Breakover current | (see Note 5) | | | ± 0.15 | | ± 0.6 | А |
| V _{TM} | Peak on-state voltage | $I_T = \pm 5 A$ | (see Notes 5 and 6) | | | ± 2.2 | ± 3 | V |
| Ι _Η | Holding current | (see Note 5) | | | ± 150 | | | mA |
| dv/dt | Critical rate of rise of off-state voltage | (see Note 7) | | | | | ± 5 | kV/μs |
| ۱ _D | Off-state leakage current | $V_D = \pm 50 V$ | | | | | ± 10 | μA |
| C _{off} | Off-state capacitance | $V_{\rm D} = 0$ | f = 1 kHz | (see Note 4) | | 110 | 200 | pF |

NOTES: 5. These parameters must be measured using pulse techniques, $t_w = 100 \ \mu$ s, duty cycle $\leq 2\%$.

6. These parameters are measured with voltage sensing contacts separate from the current carrying contacts located within 3.2 mm (0.125 inch) from the device body.

7. Linear rate of rise, maximum voltage limited to 80 % V_Z (minimum).



PARAMETER MEASUREMENT INFORMATION

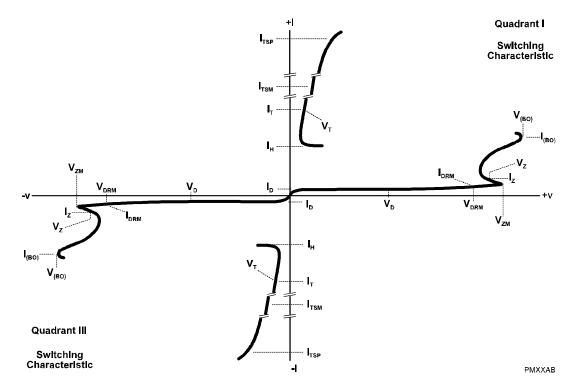


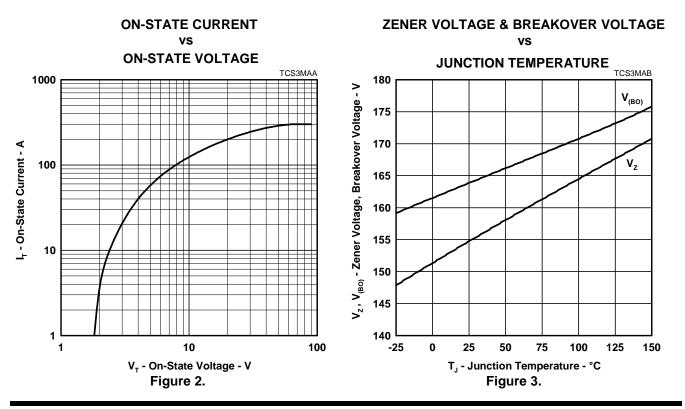
Figure 1. VOLTAGE-CURRENT CHARACTERISTIC FOR ANY PAIR OF TERMINALS

thermal characteristics

| PARAMETER | | TYP | MAX | UNIT |
|--|--|-----|------|------|
| R _{0JA} Junction to free air thermal resistance | | | 62.5 | °C/W |

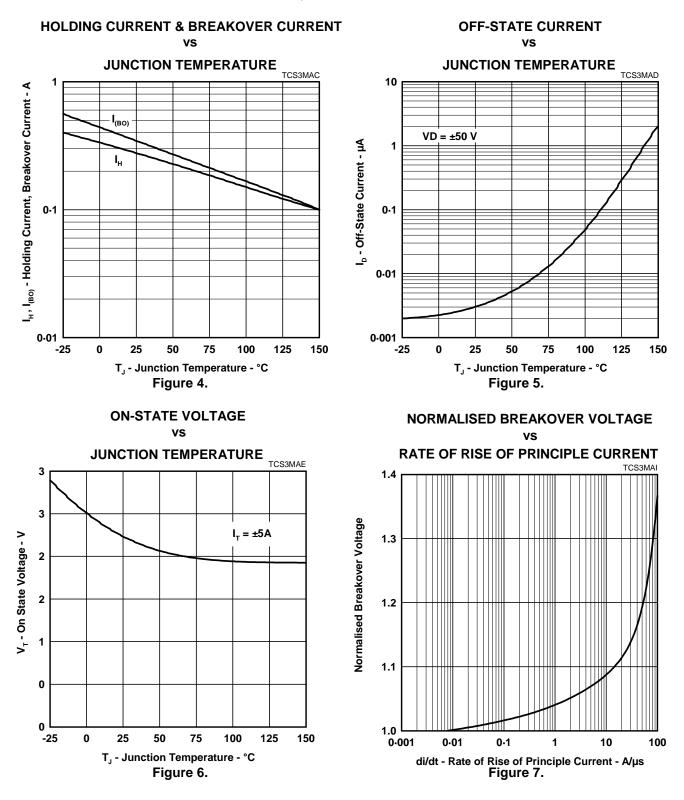


TYPICAL CHARACTERISTICS A and C, or B and C terminals



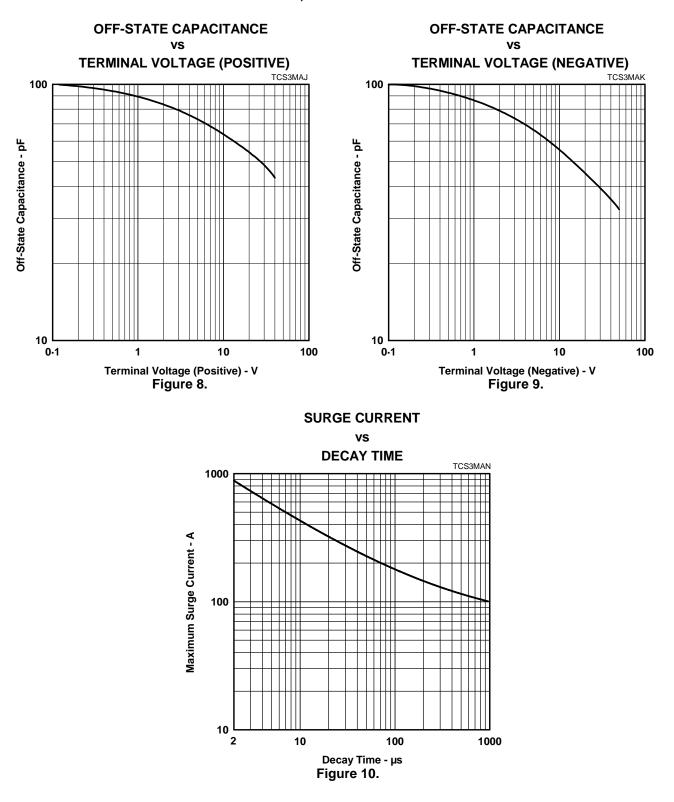


TYPICAL CHARACTERISTICS A and C, or B and C terminals



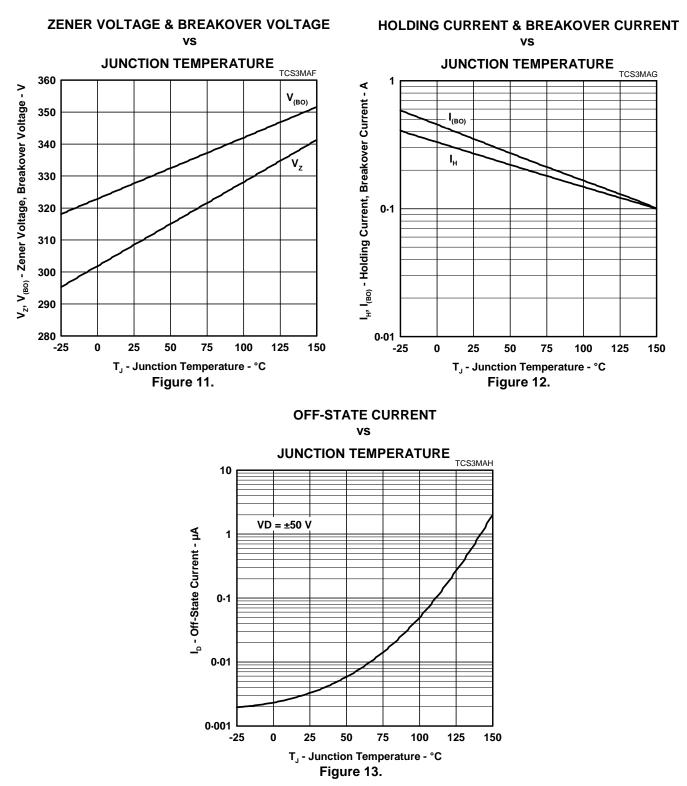


TYPICAL CHARACTERISTICS A and C, or B and C terminals





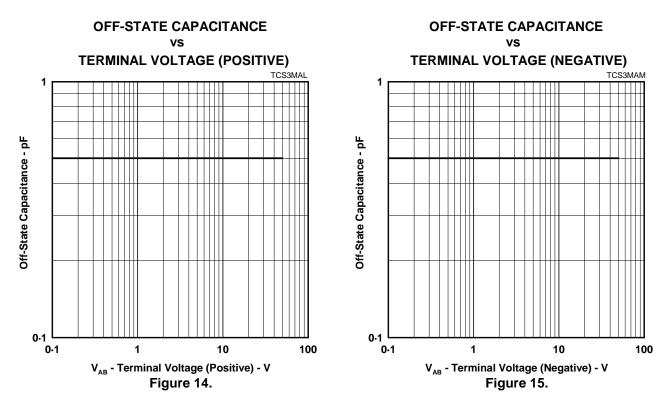
TYPICAL CHARACTERISTICS A and B terminals



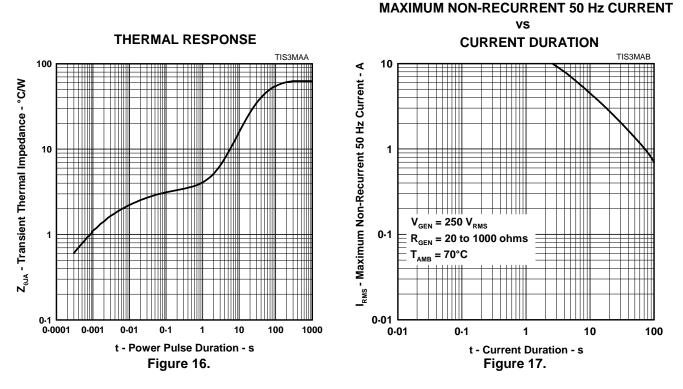


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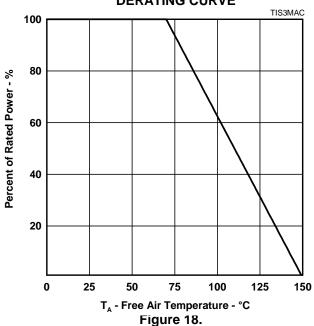
TYPICAL CHARACTERISTICS A and B terminals



THERMAL INFORMATION



FREE AIR TEMPERATURE



DERATING CURVE



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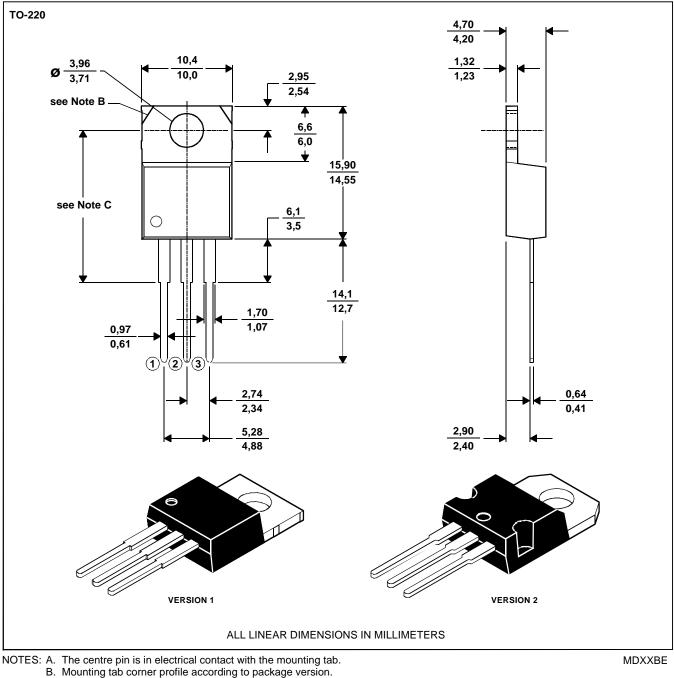
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MECHANICAL DATA

TO-220

3-pin plastic flange-mount package

This single-in-line package consists of a circuit mounted on a lead frame and encapsulated within a plastic compound. The compound will withstand soldering temperature with no deformation, and circuit performance characteristics will remain stable when operated in high humidity conditions. Leads require no additional cleaning or processing when used in soldered assembly.



C. Typical fixing hole centre stand off height according to package version. Version 1, 18.0 mm. Version 2, 17.6 mm.



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